



N-Channel 150-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^a	Q _g (Typ.)			
150	0.126 at V _{GS} = 10 V	13	9.5 nC			

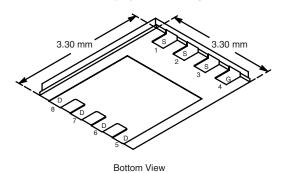
FEATURES

- Halogen-free
- TrenchFET® Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested



RoHS

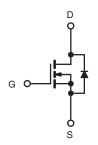
PowerPAK® 1212-8



Ordering Information: Si7620DN-T1-GE3 (Lead (Pb)-free and Halogen-free)

APPLICATIONS

· Primary Side Switch



N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	150	V	
Gate-Source Voltage		V_{GS}	± 20		
	T _C = 25 °C		13		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C		10.7		
Continuous Drain Current (1) = 150 °C)	T _A = 25 °C	- I _D	3.6 ^{b, c}	Α .	
	T _A = 70 °C		2.9 ^{b, c}	A	
Pulsed Drain Current		I _{DM}	15		
Avalanche Current	L = 0.1 mH	I _{AS}	10		
Avalanche Energy	L = U.1 IIII	E _{AS}	5	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C		13	Α	
	T _A = 25 °C	- I _S	3.2 ^{b, c}		
	T _C = 25 °C		5.2		
Maximum Power Dissipation	T _C = 70 °C	ь	33	w	
	T _A = 25 °C	P _D	3.8 ^{b, c}	VV	
	T _A = 70 °C		2 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stq} - 55 to 150		°C	
Soldering Recommendations (Peak Temperature) ^{d, e}			260		

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	24	33	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	1.9	2.4] 0/**		

Notes

- a. Based on $T_C = 25$ °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. See Solder Profile (http://www.vishay.com/ppg?73257). The PowerPAK 1212 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under Steady State conditions is 81 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	150			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		180		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	10 – 250 μΑ		- 9			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$			4.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 150 V, V _{GS} = 0 V			1	uΑ	
		$V_{DS} = 150 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			5		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	13			Α	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_D = 3.6 \text{ A}$		0.103	0.126	Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 3.6 A		10		S	
Dynamic ^b							
Input Capacitance	C _{iss}			600		pF	
Output Capacitance	C _{oss}	$V_{DS} = 75 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		50			
Reverse Transfer Capacitance	C _{rss}			15			
Total Gate Charge	Q _g			9.5	15	nC	
Gate-Source Charge	Q_{gs}	$V_{DS} = 75 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 3.6 \text{ A}$		3			
Gate-Drain Charge	Q _{gd}			2.5			
Gate Resistance	R_{g}	f = 1 MHz		1.1	2.2	Ω	
Turn-On Delay Time	t _{d(on)}			12	20	ns	
Rise Time	t _r	V_{DD} = 75 V, R_L = 26 Ω		5	10		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 2.9 A, V_{GEN} = 10 V, R_g = 1 Ω		15	25		
Fall Time	t _f			5	10		
Drain-Source Body Diode Characteristic	s			•			
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			13	Α	
Pulse Diode Forward Current	I _{SM}				15		
Body Diode Voltage	V_{SD}	I _S = 2.9 A, V _{GS} = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			50	75	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	$I_F = 2.9 \text{ A, dI/dt} = 100 \text{ A/}\mu\text{s, T}_J = 25 ^{\circ}\text{C}$		125	190	nC	
Reverse Recovery Fall Time				37		ns	
Reverse Recovery Rise Time	ne t _b			13			

Notes:

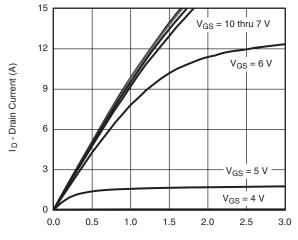
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

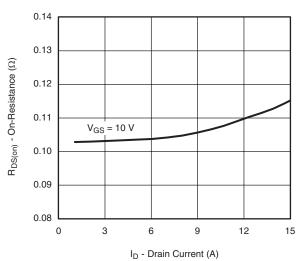


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

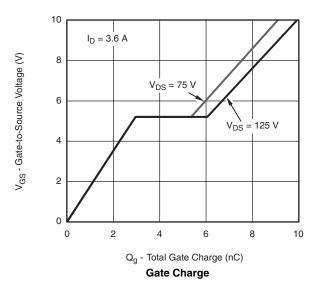


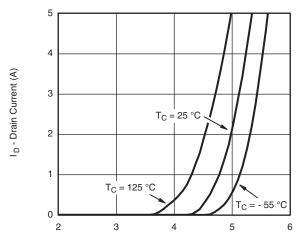
V_{DS} - Drain-to-Source Voltage (V)

Output Characteristics



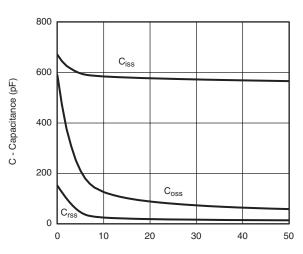
On-Resistance vs. Drain Current and Gate Voltage





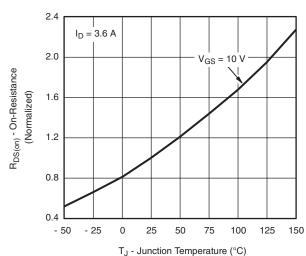
 $V_{\mbox{\footnotesize GS}}$ - Gate-to-Source Voltage (V)

Transfer Characteristics



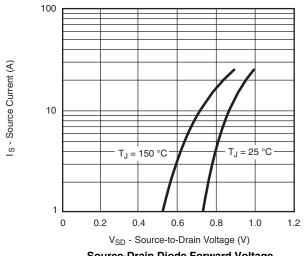
 V_{DS} - Drain-to-Source Voltage (V)

Capacitance

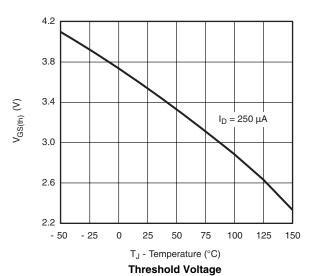


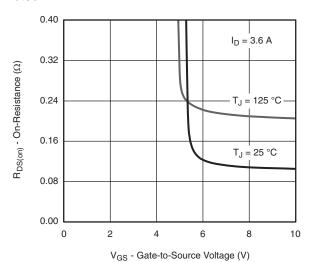
On-Resistance vs. Junction Temperature

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

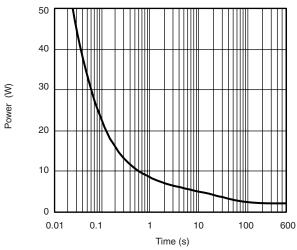


Source-Drain Diode Forward Voltage

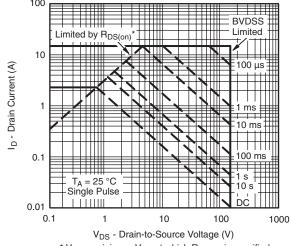




On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power (Junction-to-Ambient)



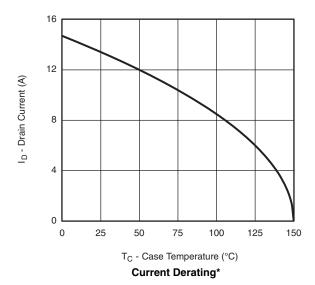
* $V_{GS} > \mbox{minimum } V_{GS}$ at which $R_{DS(on)}$ is specified

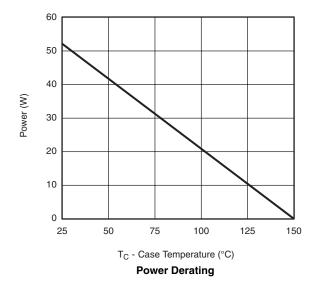
Safe Operating Area, Junction-to-Ambient





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



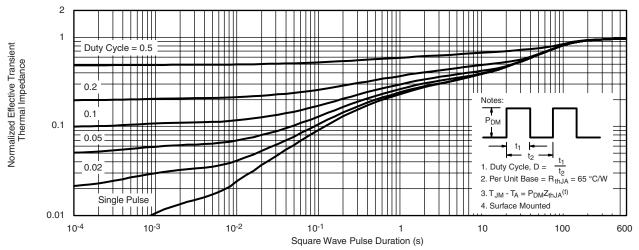


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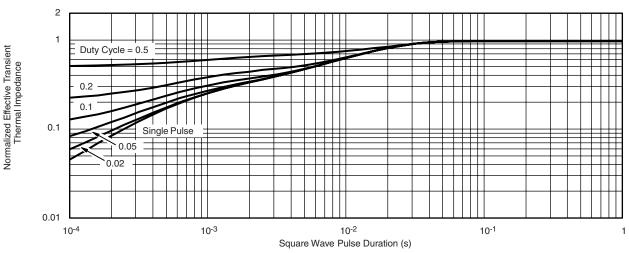
^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

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